Appendix

Please note that all Full and complete papers can be obtained by sending an email to krr_it@Yahoo.co.in

Appendix-1


Event Based and Pattern Based END-TO END Integration Testing of Embedded Systems

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Abstract

Embedded systems are event driven. The events are either system driven or initiated by an external environment through sensing devices such as Temperature sensors. The sensed data is transmitted and captured by an embedded system. The inputs are processed and the processed results are used to trigger signals that control the physical environment. The entire processing can be represented in terms of a physical thread of execution. An event process is a functional requirement, and the devices involved needs that a function be executed as per certain timing considerations and the timing is to be achieved through following a particular pattern. This paper combines the event patterns into a related thin thread and uses the patterns along with the thin threads to undertake END-TO-END testing of an Embedded System.

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